Image Denoising and Image Super-resolution for Sensing Application

Guest Editors:

Dr. Kai Zhang
Department of Information Technology and Electrical Engineering, ETH Zurich, ETH Zentrum, 8092 Zurich, Switzerland

Dr. Dongwei Ren
School of Computer Science and Technology, Harbin Institute of Technology, Harbin 150001, China

Deadline for manuscript submissions:
closed (15 June 2023)

Message from the Guest Editors

Due to the various factors during the image acquisition and transmission process, such as the poor imaging system, storage and bandwidth limitation, and insufficient computational power, the RAW sensor data and the processed images are often corrupted by noise and have low spatial resolution. Image denoising and image super-resolution, as two classical and yet active low-level vision research topics, can be applied on the RAW sensor data and the processed images to improve the image quality and the accuracy of subsequent high-level vision tasks. This Special Issue will present recent advances of image denoising and image super-resolution in sensing applications. Specifically, novel model-based methods, learning-based methods, or hybrid methods such as plug-and-play methods and deep unfolding methods for image denoising and image super-resolution will be of special attention.

Special Issue

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro
Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. *Sensors* organizes Special Issues devoted to specific sensing areas and applications each year.

Author Benefits

Open Access : free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), PubMed, MEDLINE, PMC, Ei Compendex, Inspec, Astrophysics Data System, and other databases.
Journal Rank: JCR - Q2 (*Chemistry, Analytical*) / CiteScore - Q1 (Instrumentation)

Contact Us